

# STD70N03L STD70N03L-1

## N-channel 30V - 0.0059Ω - 70A - DPAK / IPAK STripFET™ III Power MOSFET

### **General features**

Туре	V <sub>DSS</sub>	R <sub>DS(on)</sub>	۱ <sub>D</sub>
STD70N03L	30V	<0.0073Ω	70A
STD70N03L-1	30V	<0.0073Ω	70A

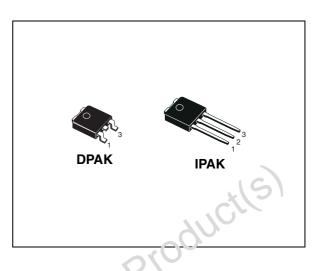
- R<sub>DS(ON)</sub> \* Qg industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

### Description

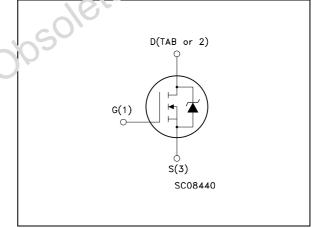
This product utilizes the latest advanced design rules of ST's proprietary STripFET<sup>™</sup> technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

### Applications

Switching application



### Internal schematic diagram



### Order codes

Part number	Marking	Package	Packaging
STD70N03L	D70N03L	DPAK	Tape & reel
STD70N03L-1	D70N03L-1	IPAK	Tube

June 2006

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#### **Electrical ratings** 1

Table 1.	Absolute	maximum	ratings
	Abounde	IIIuAIIIIuIII	runngo

Symbol	Parameter	Value	Unit				
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	30	V				
V <sub>GS</sub>	Gate-source voltage	± 20	V				
I <sub>D</sub>	Drain current (continuous) at $T_C = 25^{\circ}C$	70	А				
I <sub>D</sub>	Drain current (continuous) at $T_C = 100^{\circ}C$	50	А				
I <sub>DM</sub> <sup>(1)</sup>	Drain current (pulsed)	280	А				
P <sub>TOT</sub>	Total dissipation at $T_C = 25^{\circ}C$	70	W				
	Derating factor	0.47	W/°C				
E <sub>AS</sub> <sup>(2)</sup>	Single pulse avalanche energy	300	mJ				
T <sub>j</sub> T <sub>stg</sub>	Operating junction temperature Storage temperature	-55 to 175	°C				
	n limited by safe operating area =25°C, Id = 30A, Vdd = 15V	01/00					
Table 2.	Table 2.   Thermal resistance						
Symbol	Parameter	Value	Unit				

Table 2.	Thermal resistance

	Symbol	Parameter	Value	Unit
	Rthj-case	Thermal resistance junction-case Max	2.14	°C/W
	Rthj-amb	Thermal resistance junction-amb Max	100	°C/W
	Τ <sub>Ι</sub>	Maximum lead temperature for soldering purpose	275	°C
obsole	stePr	odulu		

#### **Electrical characteristics** 2

(T<sub>CASE</sub>=25°C unless otherwise specified)

Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 250μΑ, V <sub>GS</sub> = 0	30			V
I <sub>DSS</sub>	Zero gate voltage drain current ( $V_{GS} = 0$ )	V <sub>DS</sub> = 20V, V <sub>DS</sub> = 20V,Tc = 125°C			1 10	μΑ μΑ
I <sub>GSS</sub>	Gate body leakage current(V <sub>DS</sub> = 0)	$V_{GS} = \pm 20V$			±100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1			V
R <sub>DS(on)</sub>	Static drain-source on resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 35A V <sub>GS</sub> = 5V, I <sub>D</sub> = 35A V <sub>GS</sub> = 10V, I <sub>D</sub> = 35A @Tj=125°C V <sub>GS</sub> = 5V, I <sub>D</sub> = 35A @Tj=125°C		0.0059 0.007 0.0091 0.0108	0.0073 0.013 0.0113 0.0201	Ω Ω Ω
Table 4.	Dynamic		24			

#### Table 3. **On/off states**

#### Table 4. Dynamic

Symb	Parameter	Test condictions	Min.	Тур.	Max.	Unit
9 <sub>fs</sub> (1)	Forward transconductance	V <sub>DS</sub> =10V, I <sub>D</sub> = 15A		40		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	V <sub>DS</sub> =25V, f=1MHz, V <sub>GS</sub> =0		2200 380 49		pF pF pF
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	V <sub>DD</sub> =15V, I <sub>D</sub> = 70A V <sub>GS</sub> =5V <i>(see Figure 7)</i>		15.7 8.3 3.4	21	nC nC nC
Q <sub>gls</sub> (2	Third-quadrant gate charge	V <sub>DS</sub> <0V, V <sub>GS</sub> =10V		15		nC
R <sub>G</sub>	Gate input resistance	f=1MHz Gate DC Bias =0 Test signal level =20mV open drain		1.5		Ω

	<b>–</b>				1	
Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub> t <sub>r</sub> t <sub>d(off)</sub> t <sub>f</sub>	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD}$ =15V, I <sub>D</sub> =35A, R <sub>G</sub> =4.7 $\Omega$ , V <sub>GS</sub> =5V (see Figure 13)		21 95 19 15		ns ns ns ns

Table 5. Switching times

#### Table 6. Source drain diode

Symbol	Parameter	Test condictions	Min	Тур.	Max	Unit
I <sub>SD</sub>	Source-drain current				70	А
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				280	А
$V_{SD}^{(2)}$	Forward on voltage	I <sub>SD</sub> =35A, V <sub>GS</sub> =0			1.3	V
t <sub>rr</sub>	Reverse recovery time	$I_{SD} = 70A$ ,		32	X.	ns
Q <sub>rr</sub>	Reverse recovery charge	di/dt=100A/µs, V <sub>DD</sub> =20V, Tj=150°C		51		nC
I <sub>RRM</sub>	Reverse recovery current	(see Figure 18)		3.2		А
ste P	dth limited by safe operating area bulse duration = 300µs, duty cycle 1.59	bsole				



 $Z_{th} = k R_{thJ-c}$ 

10<sup>-1</sup> † p (s)

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 $\delta = t_p / \tau$ 

280DPI

**Thermal impedance** 

0.05

10-3

**Transfer characteristics** 

0.01

10-2

SINGLE PULSE

10-4

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 $\delta = 0.5$ 

κ

10

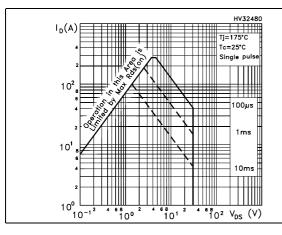
10 -2

Figure 4.

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### 2.1 Electrical characteristics (curves)

### Figure 1. Safe operating area





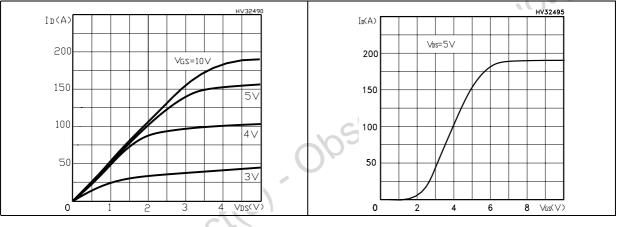
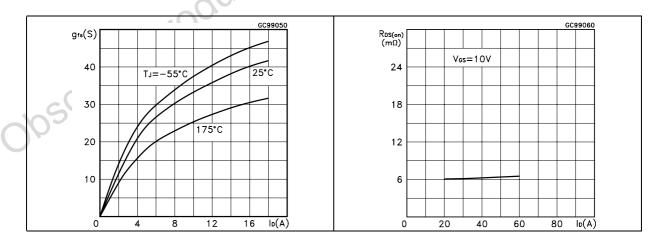


Figure 2.







### Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

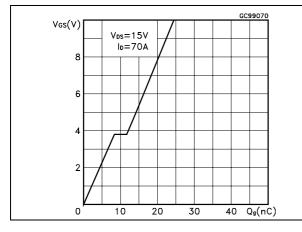


Figure 9. Normalized gate threshold voltage vs temperature

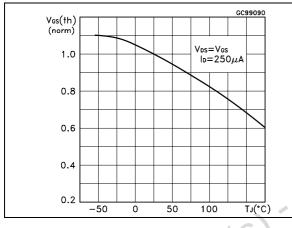


Figure 11. Source-drain diode forward characteristics

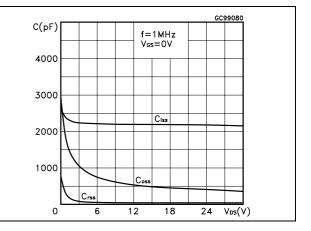


Figure 10. Normalized on resistance vs temperature

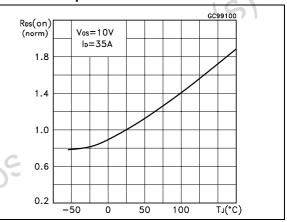
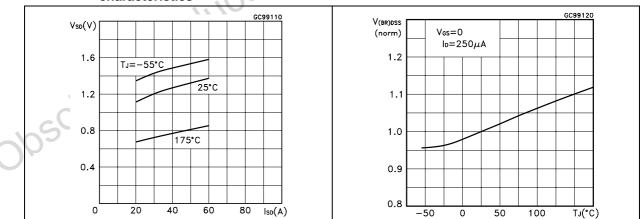


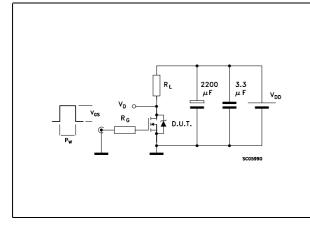
Figure 12. Normalized B<sub>VDSS</sub> vs temperature



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### 3 Test circuit

Figure 13. Switching times test circuit for resistive load



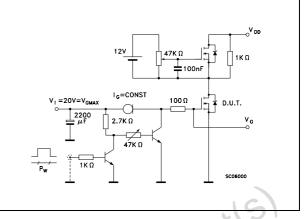
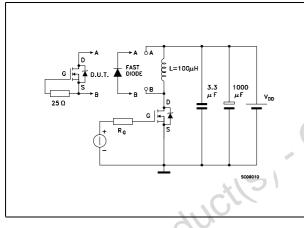


Figure 14. Gate charge test circuit

Figure 15. Test circuit for inductive load switching and diode recovery times





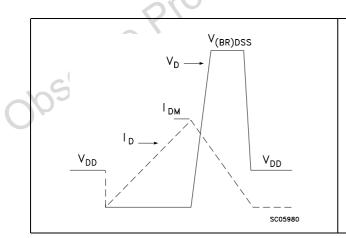




Figure 16. Unclamped inductive load test circuit

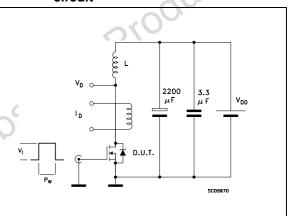
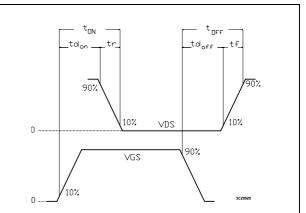


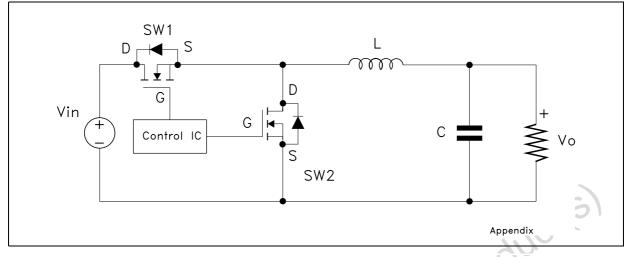
Figure 18. Switching time waveform



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### Appendix A Power losses estimation

### Figure 19. Buck converter



The power losses associated with the FETs in a synchronous buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the wotking temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

The low side (SW2) device requires:

- Very low R<sub>DS(on)</sub> to reduce conduction losses
- Small Q<sub>als</sub> to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Q<sub>rr</sub> to reduce losses on SW<sub>1</sub> during its turn-on
- The C<sub>gd</sub>/C<sub>gs</sub> ratio lower than V<sub>th</sub>/V<sub>gg</sub> ratio especially with low drain to source voltage to avoid the cross conduction phenomenon.

The high side (SW1) device requires:

- Small Rg and Lg to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Q<sub>a</sub> to have a faster commutation and to reduce gate charge losses
- Low R<sub>DS(on)</sub> to reduce the conduction losses



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		High side switch (SW1)	Low side switch (SW2)
P <sub>conduction</sub>	on	$R_{DS(on)} \bullet I_L^2 \bullet \delta$	$R_{DS(on)} \bullet I_L^2 \bullet (1 - \delta)$
P <sub>switching</sub>		$V_{in} \bullet (Q_{gsth(SW1)} + Q_{gd(SW1)}) \bullet f \bullet \frac{I_L}{I_g}$	Zero voltage switching
P <sub>diode</sub>	Recovery	Not applicable	$^{1}V_{in} \bullet Q_{rr(SW2)} \bullet f$
uloue	Conduction	Not applicable	V <sub>f(SW2)</sub> • I <sub>L</sub> • t <sub>deadtime</sub> • f
P <sub>gate(Qg)</sub>		$Q_{g(SW1)} \bullet V_{gg} \bullet f$	Q <sub>gls(SW2)</sub> ● V <sub>gg</sub> ● f
P <sub>Qoss</sub>		$\frac{V_{in} \bullet Q_{oss(SW1)} \bullet f}{2}$	$\frac{V_{in} \bullet Q_{oss(SW2)} \bullet f}{2}$
		dus	

Parameter	Meaning
d	Duty-cycle
Q <sub>gsth</sub>	Post threshold gate charge
Q <sub>gls</sub>	Third quadrant gate charge
Pconduction	On state losses
Pswitching	On-off transition losses
Pdiode	Conduction and reverse recovery diode losses
Pgate	Gate driver losses
P <sub>Qoss</sub>	Output capacitance losses

### 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

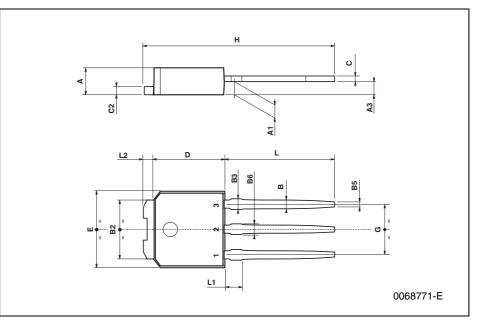
obsolete Product(s). Obsolete Product(s)



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		mm		inch			
DIM.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	2.2		2.4	0.086		0.094	
A1	0.9		1.1	0.035		0.043	
A3	0.7		1.3	0.027		0.051	
В	0.64		0.9	0.025		0.031	
B2	5.2		5.4	0.204		0.212	
B3			0.85			0.033	
B5		0.3			0.012		
B6			0.95			0.037	
С	0.45		0.6	0.017		0.023	
C2	0.48		0.6	0.019		0.023	
D	6		6.2	0.236		0.244	
E	6.4		6.6	0.252		0.260	
G	4.4		4.6	0.173		0.181	
Н	15.9		16.3	0.626		0.641	
L	9		9.4	0.354		0.370	
L1	0.8		1.2	0.031		0.047	
L2		0.8	1		0.031	0.039	





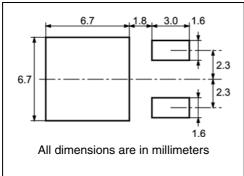


	DPAK MECHANICAL DATA					
	mm.				inch	
DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
A	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
e		2.28			0.090	1
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°
	H H					
ole		<u>SEATING PLANE</u>	an			

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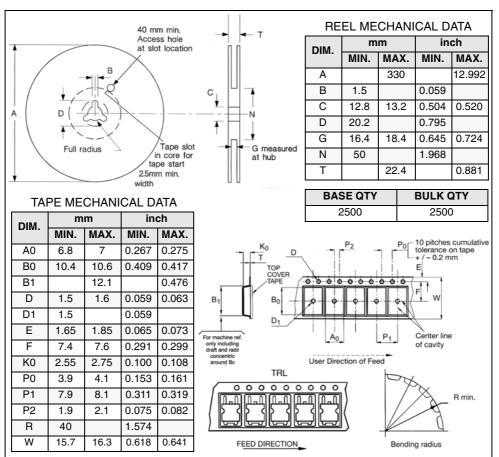


## 5 Packaging mechanical data



# DPAK FOOTPRINT





## 6 Revision history

### Table 7. Revision history

Date	Revision	Changes		
29-Jun-2006	1	First Release		

obsolete Product(s). Obsolete Product(s)



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